



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1410-01 DATE: 29-Oct-2014 Product Affected: F0552NLGI, F0552NLGI8 Date Effective: 29-Jan-2015	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark Traceability to the test location is <input type="checkbox"/> Date Code maintained by IDT and available on <input checked="" type="checkbox"/> Other request
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Contact: IDT PCN DESK E-mail: pcndesk@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Please contact your local sales representative for sample request.
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DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>This notification is to advise our customers that IDT is adding UTAC, Singapore (USG) as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility.</p> <p>Attachment I details the change.</p>
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RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____
CUSTOMER COMMENTS: _____	

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT I - PCN # : TB1410-01

PCN Type: Manufacturing Site - Alternate Test Location

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT is adding UTAC, Singapore (USG) as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards and test programs are the same at both qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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Qualification Information and Qualification Data:

Electrical Test Correlation Results

Vehicle: F0552NLGI

Sample size: 500 electrically good units and 10 reject units

Description	Existing Test (IDT - IDT, Penang)	Alternate Test (USG - UTAC, Singapore)
Tester Platform	LTX	LTX
Loadboard	ME113C	ME113C
Test Program	IDTF0552NBGI_CB_SEQ0603	IDTF0552NBGI_CB_SEQ0603
Test Site	Single Site	Single Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units Correlated @ ambient	500 pcs	500 pcs
500 units Bin 1 handler run (good units)	Passed	Passed
Number of Reject Units Correlated @ ambient	10 pcs	10 pcs
10 units rejects handler run	Passed	Passed
500 units Bin 1 datalog correlation (good units)	Passed	Passed
10 units rejects datalog correlation	Passed	Passed